

# **Notice of References Cited**

Applicant/Patent  
**Chang et al.**

Application/Control No.  
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Examiner  
**Curtis Mayes**

Art Unit  
**1734**

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	Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>	
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## **NON-PATENT DOCUMENTS**

	Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
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